## Search Notes

| Application No. | Applicant(s)    |  |
|-----------------|-----------------|--|
| 10/654,403      | OGISHIMA ET AL. |  |
| Examiner        | Art Unit        |  |
| Toan Ton        | 2871            |  |

|       | SEAR     | CHED     |          |
|-------|----------|----------|----------|
| Class | Subclass | Date     | Examiner |
| 349   | 130      | 7/6/2004 | TTON     |
|       | 177      |          |          |
|       | 180      |          |          |
|       | 181      |          |          |
|       | 143      |          |          |
| •     | 129      |          |          |
|       |          |          |          |
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| INI   | INTERFERENCE SEARCHED |          |          |
|-------|-----------------------|----------|----------|
| Class | Subclass              | Date     | Examiner |
| 349   | 130,143               | 7/9/2004 | TTON     |
|       | 177,180               |          |          |
|       | 181,129               |          |          |
|       |                       |          |          |
|       |                       |          |          |

| SEARCH NOTES (INCLUDING SEARCH STRATEGY)  |          |      |  |
|---|----------|------|--|
|   | DATE     | EXMR |  |
| EAST iquid crystal (v voltage) max bitch delta n thick, thickness ambda/wavelength wist ppenings, apertures domains | 7/6/2004 | TTON |  |
|   |          |      |  |
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